

Notice of References Cited	Application/Control No. 10/796,147	Applicant(s)/Patent Under Reexamination CHIN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 07027426 A	01-1995	Japan	NOGUCHI et al.	
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